## Application/Control No. Applicant(s)/Patent Under Reexamination 10/008,119 WEI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Shervin Nakhjavan 2621 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,690,816 B2 02-2004 Aylward et al. 382/128 Α US-6,678,399 B2 01-2004 Doi et al. 382/131 В C US-2003/0099390 A1 05-2003 Zeng et al. 382/131 D US-2003/0095692 A1 05-2003 Mundy et al. 382/128 Ε US-2003/0028401 A1 02-2003 Kaufman et al. 705/3 F US-US-G US-Н USt J US-Κ US-US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ

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